## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10590630	JENSEN ET AL.
Examiner	Art Unit
Young J Kim	1637

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES			
Search Notes	Date	Examiner	
reviewed search strategy for 10/590,632	11/14/2008	/YJK/	
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB) - see enclosed for text-search strategy	8/6/2009	/YJK/	
NPL - search terms: spore, lysis, alternating electric field, bacterial/bacteria spore.	8/6/2009	/YJK/	

INTERFERENCE SEARCH				
Class	Subclass	Date	Examiner	
	Interference history - see enclosed	10/7/2010	/YJK/	

	/Young J Kim/ Primary Examiner.Art Unit 1637
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